

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- ☐ **BLACK BORDERS**
- ☐ **IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- ☐ **FADED TEXT OR DRAWING**
- ☐ **BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- ☐ **SKEWED/SLANTED IMAGES**
- ☐ **COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- ☐ **GRAY SCALE DOCUMENTS**
- ☐ **LINES OR MARKS ON ORIGINAL DOCUMENT**
- ☐ **REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- ☐ **OTHER:** _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.

10/047, 289

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®

Welcome
United States Patent and Trademark OfficeIEEE Xplore®
1 Million Documents
1 Million Users

Help FAQ Terms IEEE Peer Review

Quick Links

» Search Results

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Index of Contents

- ☐ Journals & Magazines
- ☐ Conferences Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **2 of 1094442** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

(queiroz<in>au) <and> (optimizing<in>ti)

Search

☐ Check to search within this result set**Results Key:**

JNL = Journal or Magazine CNF = Conference STD = Standard


1 Optimizing block-thresholding segmentation for multilayer compression of compound imagesde Queiroz, R.L.; Zhigang Fan; Tran, T.D.;
Image Processing, IEEE Transactions on , Volume: 9 , Issue: 9 , Sept. 2000
Pages: 1461 - 1471

[Abstract] [PDF Full-Text (448 KB)] IEEE JNL

2 Optimizing block-threshold segmentation for MRC compressionde Queiroz, R.L.; Zhigang Fan; Tran, T.D.;
Image Processing, 2000. Proceedings. 2000 International Conference on , Volume: 2 , 10-13 Sept. 2000
Pages: 597 - 600 vol.2

[Abstract] [PDF Full-Text (388 KB)] IEEE CNF

 Access the
IEEE Embroidery
File Cabinet

 Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications Services Standards Conferences Proceedings

IEEE Xplore

Welcome
United States Patent and Trademark Office



IEEE Xplore®
1 Million Documents
1 Million Users

Help FAQ Terms IEEE Peer Review

Quick Links



» Search Results

Welcome to IEEE Xplore

☐ Home

☐ What Can I Access?

☐ Log-on!

☐ Publications

☐ Journals & Magazines

☐ Conference Proceedings

☐ Standards

☐ Search

☐ By Author

☐ Basic

☐ Advanced

☐ CrossRef

☐ Member Services

☐ Join IEEE

☐ Establish IEEE

☐ Web Account

☐ Access the

☐ IEEE Member Digital Library

Your search matched **6 of 1094442** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

Search

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

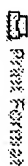
1 **Linear-phase perfect reconstruction filter bank: lattice structure, design, and application in image coding**
Tran, T.D.; de Queiroz, R.L.; Nguyen, T.Q.;
Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 48, Issue: 1, Jan. 2000
Pages:133 - 147

[Abstract] [PDF Full-Text (536 KB)] IEEE JNL

2 **Optimizing block-thresholding segmentation for multilayer compression of compound images**
de Queiroz, R.L.; Zhigang Fan; Tran, T.D.;
Image Processing, IEEE Transactions on , Volume: 9, Issue: 9, Sept. 2000
Pages:1461 - 1471

[Abstract] [PDF Full-Text (448 KB)] IEEE JNL

Access the
IEEE Manuscript
File Content



3 Optimizing block-threshold segmentation for MRC compression
de Queiroz, R.L.; Zhigang Fan; Tran, T.D.;
Image Processing, 2000. Proceedings. 2000 International Conference on , Volume:
2, 10-13 Sept. 2000
Pages: 597 - 600 vol. 2

[Abstract] [PDF Full-Text (388 KB)] IEEE CNF

4 Compression of compound documents
de Queiroz, R.L.;
Image Processing, 1999. ICIP 99. Proceedings. 1999 International Conference
on , Volume: 1, 1999
Pages: 209 - 213 vol. 1

[Abstract] [PDF Full-Text (520 KB)] IEEE CNF

**5 Adaptive rate-distortion-based thresholding: application in JPEG
compression of mixed images for printing**
Ramos, M.; de Queiroz, R.L.;
Acoustics, Speech, and Signal Processing, 1999. ICASSP '99. Proceedings., 1999
IEEE International Conference on , Volume: 5, 15-19 March 1999
Pages: 2431 - 2434 vol. 5

[Abstract] [PDF Full-Text (360 KB)] IEEE CNF

6 The generalized lapped biorthogonal transform
Tran, T.D.; de Queiroz, R.; Nguyen, T.Q.;
Acoustics, Speech, and Signal Processing, 1998. ICASSP '98. Proceedings of the
1998 IEEE International Conference on , Volume: 3, 12-15 May 1998
Pages: 1441 - 1444 vol. 3

[Abstract] [PDF Full-Text (508 KB)] IEEE CNF

Home | Log Out | Navigation | Conference Proceedings | Standards | Search by Author | Manuscript | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your
Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved